











TLV314-Q1, TLV2314-Q1, TLV4314-Q1

SBOS837-NOVEMBER 2016

TLVx314-Q1 3-MHz, Low-Power, Internal EMI Filter, RRIO, Operational Amplifier

Features

- **Qualified for Automotive Applications**
- AEC-Q100 Qualified With the Following Results:
 - Device Temperature Grade 1: –40°C to +125°C Ambient Operating Temperature Range
 - Device HBM ESD Classification Level 3A
 - Device CDM ESD Classification Level C6
- Low Offset Voltage: 0.75 mV (Typical)
- Low Input Bias Current: 1 pA (Typical)
- Wide Supply Range: 1.8 V to 5.5 V
- Rail-to-Rail Input and Output
- Gain Bandwidth: 3 MHz
- Low Io: 250 µA/Ch (Maximum)
- Low Noise: 16 nV/√Hz at 1 kHz
- Internal RF and EMI Filter
- Number of Channels:
 - TLV314-Q1: 1
 - TLV2314-Q1: 2
 - TLV4314-Q1: 4
- Extended Temperature Range:
 - -40°C to +125°C

2 Applications

- Low-Side Sensing
- **Battery Management Systems**
- Passive Safety
- Capacitive Sensing
- **Fuel Pumps**

3 Description

The TLVx314-Q1 family of single-, dual-, and quadchannel operational amplifiers represents a new generation of low-power, general-purpose operational amplifiers. Rail-to-rail input and output swings (RRIO), low quiescent current (150 µA typically at 5 V) combine with a wide bandwidth of 3 MHz to make this family very attractive for a variety of batterypowered applications that require a good balance between cost and performance. The TLVx314-Q1 family achieves a low-input bias current of 1 pA, making it an excellent choice for high impedance sensors.

The robust design of the TLVx314-Q1 devices provides ease-of-use to the circuit designer: unitygain stability, RRIO, capacitive loads of up to 300-pF, an integrated RF and EMI rejection filter, no phase reversal in overdrive conditions, and high electrostatic discharge (ESD) protection (4-kV HBM).

These devices are optimized for low-voltage operation as low as 1.8 V (±0.9 V) and up to 5.5 V (±2.75 V), and are specified over the extended industrial temperature range of -40°C to +125°C.

The TLV314-Q1 (single) is available in both 5-pin SC70 and SOT-23 packages. The TLV2314-Q1 (dual) is offered in 8-pin SOIC and VSSOP packages. The quad-channel TLV4314-Q1 is offered in a 14-pin TSSOP package.

Device Information⁽¹⁾

PART NUMBER PACKAGE BODY SIZE (NO		BODY SIZE (NOM)
TI V244 O4	SOT-23 (5)	2.90 mm × 1.60 mm
TLV314-Q1	SC70 (5)	2.00 mm × 1.25 mm
TI \ (004.4.04	VSSOP (8)	3.00 mm × 3.00 mm
TLV2314-Q1	SOIC (8)	4.90 mm × 3.91 mm
TLV4314-Q1	TSSOP (14)	5.00 mm × 4.40 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

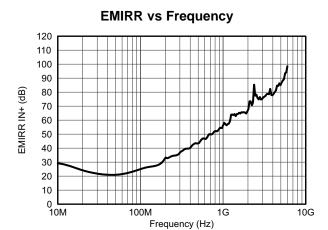






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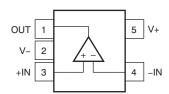
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4 Revision History

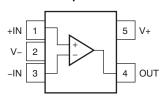
DATE	REVISION	NOTES
November 2016	SBOS837*	Initial release.

5 Pin Configuration and Functions

TLV314-Q1 DBV Package 5-Pin SOT-23 Top View



TLV314-Q1 DCK Package 5-Pin SC70 Top View

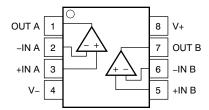


Pin Functions: TLV314-Q1

	PIN				
NAME	DBV (SOT-23)	DCK (SC70)	I/O	DESCRIPTION	
-IN	4	3	I	Inverting input	
+IN	3	1	I	Noninverting input	
OUT	1	4	0	Output	
V-	2	2	_	Negative (lowest) supply	
V+	5	5	_	Positive (highest) supply	



TLV2314-Q1 D, DGK Packages 8-Pin SOIC or VSSOP Top View

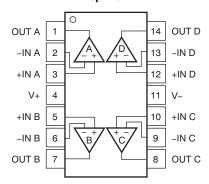


Pin Functions: TLV2314-Q1

PIN		1/0	DESCRIPTION
NAME	NO.	1/0	DESCRIPTION
–IN A	2	1	Inverting input, channel A
+IN A	3	1	Noninverting input, channel A
–IN B	6	1	Inverting input, channel B
+IN B	5	1	Noninverting input, channel B
OUT A	1	0	Output, channel A
OUT B	7	0	Output, channel B
V-	4	_	Negative (lowest) supply
V+	8	_	Positive (highest) supply



TLV4314-Q1 PW Package 14-Pin TSSOP Top View



Pin Functions: TLV4314-Q1

PIN I/O		1/0	DESCRIPTION
NAME	NO.	1/0	DESCRIPTION
–IN A	2	1	Inverting input, channel A
+IN A	3	1	Noninverting input, channel A
–IN B	6	1	Inverting input, channel B
+IN B	5	I	Noninverting input, channel B
–IN C	9	I	Inverting input, channel C
+IN C	10	I	Noninverting input, channel C
–IN D	13	I	Inverting input, channel D
+IN D	12	I	Noninverting input, channel D
OUT A	1	0	Output, channel A
OUT B	7	0	Output, channel B
OUT C	8	0	Output, channel C
OUT D	14	0	Output, channel D
V-	11	_	Negative (lowest) supply
V+	4	_	Positive (highest) supply



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted). (1)

		MIN	MAX	UNIT
Supply voltage			7	V
Cinnal innut nina	Voltage ⁽²⁾	(V-) - 0.5	(V+) + 0.5	V
Signal input pins	Current ⁽²⁾	-10	10	mA
Output short-circuit (3)		Con	Continuous	
	Specified, T _A	-40	125	
Temperature	Junction, T _J		150	°C
	Storage, T _{stg}	–65	150	

⁽¹⁾ Stresses above these ratings may cause permanent damage. Exposure to absolute maximum conditions for extended periods may degrade device reliability. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those specified is not supported.

6.2 ESD Ratings

			VALUE	UNIT
V _(ESD) Electrostatic discharge		Human-body model (HBM), per AEC Q100-002 ⁽¹⁾	±4000	
	Charged-device model (CDM), per AEC Q100-011	±1000	V	

⁽¹⁾ AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

			MIN	NOM MAX	UNIT
V	Supply voltage	Single-supply	1.8	5.5	
V _S Supply volta	Supply voltage	Dual-supply	±0.9	±2.75	V
	Specified temperature range		-40	125	°C

⁽²⁾ Input pins are diode-clamped to the power-supply rails. Input signals that can swing more than 0.5 V beyond the supply rails must be current limited to 10 mA or less.

⁽³⁾ Short-circuit to ground, one amplifier per package.

6.4 Thermal Information: TLV314-Q1

		TLV3	TLV314-Q1		
	THERMAL METRIC ⁽¹⁾	DBV (SOT-23)	DCK (SC70)	UNIT	
		5 PINS	5 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	228.5	281.4	°C/W	
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	99.1	91.6	°C/W	
$R_{\theta JB}$	Junction-to-board thermal resistance	54.6	59.6	°C/W	
ΨЈΤ	Junction-to-top characterization parameter	7.7	1.5	°C/W	
ΨЈВ	Junction-to-board characterization parameter	53.8	58.8	°C/W	

⁽¹⁾ For more information about traditional and new thermal metrics, see Semiconductor and IC Package Thermal Metrics (SPRA953).

6.5 Thermal Information: TLV2314-Q1

		TLV	TLV2314-Q1		
	THERMAL METRIC(1)	D (SOIC)	DGK (VSSOP)	UNIT	
		8 PINS	8 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	138.4	191.2	°C/W	
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	89.5	61.9	°C/W	
$R_{\theta JB}$	Junction-to-board thermal resistance	78.6	111.9	°C/W	
ΨЈТ	Junction-to-top characterization parameter	29.9	5.1	°C/W	
ΨЈВ	Junction-to-board characterization parameter	78.1	110.2	°C/W	

⁽¹⁾ For more information about traditional and new thermal metrics, see Semiconductor and IC Package Thermal Metrics (SPRA953).

6.6 Thermal Information: TLV4314-Q1

		TLV4314-Q1	
	THERMAL METRIC ⁽¹⁾	PW (TSSOP)	UNIT
		14 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	121	°C/W
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	49.4	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	62.8	°C/W
ΨЈТ	Junction-to-top characterization parameter	5.9	°C/W
ΨЈВ	Junction-to-board characterization parameter	62.2	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see Semiconductor and IC Package Thermal Metrics (SPRA953).

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6.7 Electrical Characteristics

 $V_S = 1.8 \text{ V}$ to 5.5 V; at $T_A = 25$ °C, $R_L = 10 \text{ k}\Omega$ connected to $V_S / 2$, $V_{CM} = V_S / 2$, and $V_{OUT} = V_S / 2$ (unless otherwise noted)⁽¹⁾

	PARAMETE	R	TEST CONDITIONS	MIN TYP	MAX	UNIT
OFFSET	VOLTAGE					
V _{os}	Input offset voltage		V _{CM} = (V _S +) - 1.3 V, T _A = 25°C	±0.75	±3	mV
dV _{OS} /dT	V _{OS} vs temperature		T _A = -40°C to +125°C	2		μV/°C
PSRR	Power-supply rejection	on ratio	V _{CM} = (V _S +) - 1.3 V, T _A = 25°C	±30	±135	μV/V
	Channel separation,		At dc, $T_A = 25^{\circ}C$	100		dB
INPUT V	OLTAGE RANGE		<u> </u>			
V _{CM}	Common-mode volta	ge range	T _A = 25°C	(V-) - 0.2	(V+) + 0.2	V
CMRR			$V_S = 5.5 \text{ V}, (V_{S}-) - 0.2 \text{ V} < V_{CM} < (V_{S}+) - 1.3 \text{ V},$ $T_A = 25^{\circ}\text{C}$	72 96		dB
Common mode rejection ratio			$V_S = 5.5 \text{ V}, V_{CM} = -0.2 \text{ V to } 5.7 \text{ V}^{(2)}, T_A = 25^{\circ}\text{C}$	75		
INPUT B	IAS CURRENT					
I _B	Input bias current		T _A = 25°C	±1.0		pA
I _{OS}	Input offset current		T _A = 25°C	±1.0		pA
NOISE						
	Input voltage noise (peak-to-peak)		f = 0.1 Hz to 10 Hz, T _A = 25°C	5		μV_{PP}
		· · · · · ·	$f = 10 \text{ kHz}, T_A = 25^{\circ}\text{C}$	15		nV/√Hz
e _n	Input voltage noise d	ensity	f = 1 kHz, T _A = 25°C	16		
i _n	Input current noise d	ensity	f = 1 kHz, T _A = 25°C	6		fA/√Hz
	APACITANCE		,			
	ALACITANCE	Differential	V _S = 5 V, T _A = 25°C	1		
C_{IN}	Input capacitance	Common-mode	V _S = 5 V, T _A = 25°C	5		pF
OPEN-I (OOP GAIN	Common mode	VS = 5 V, TA = 25 C			L
			$V_S = 1.8 \text{ V to } 5.5 \text{ V}, 0.2 \text{ V} < V_O < (V+) - 0.2 \text{ V}, $ 85 115 $R_L = 10 \text{ k}\Omega, T_A = 25^{\circ}\text{C}$			
A _{OL}	Open-loop voltage gain		V_S = 1.8 V to 5.5 V, 0.5 V < V_O < (V+) - 0.5 V, R_L = 2 k $\Omega^{(2)}$, T_A = 25°C	85 100		dB
	Phase margin		$V_S = 5 \text{ V}, \text{ G} = 1, \text{ R}_L = 10 \text{ k}\Omega, \text{ T}_A = 25^{\circ}\text{C}$	65		0
FREQUE	NCY RESPONSE			<u>'</u>		
			$V_S = 1.8 \text{ V}, R_L = 10 \text{ k}\Omega, C_L = 10 \text{ pF}, T_A = 25 ^{\circ}\text{C}$	2.7		
GBW	Gain-bandwidth prod	uct	$V_S = 5 \text{ V}, R_L = 10 \text{ k}\Omega, C_L = 10 \text{ pF}, T_A = 25^{\circ}\text{C}$			MHz
SR	Slew rate ⁽³⁾		V _S = 5 V, G = 1, T _A = 25°C	1.5		V/µs
t _S	Settling time		To 0.1%, V _S = 5 V, 2-V step , G = 1, T _A = 25°C	3		μS
	Overload recovery tir	ne	$V_S = 5 \text{ V}, V_{IN} \times \text{gain} > V_S, T_A = 25^{\circ}\text{C}$	8		μS
THD+N	Total harmonic distor		$V_S = 5 \text{ V}, V_O = 1 \text{ V}_{RMS}, G = 1, f = 1 \text{ kHz},$ $R_L = 10 \text{ k}\Omega, T_A = 25^{\circ}\text{C}$	0.005%		
OUTPUT	•					
Vo	Voltage output swing	from supply rails	$V_S = 1.8 \text{ V to } 5.5 \text{ V}, R_L = 10 \text{ k}\Omega, T_A = 25^{\circ}\text{C}$	5		mV
	Short-circuit current		$V_S = 1.8 \text{ V to } 5.5 \text{ V}, R_L = 2 \text{ k}\Omega, T_A = 25^{\circ}\text{C}$	22 ±20		
I _{SC}		nadanaa	$V_S = 5 \text{ V}, T_A = 25^{\circ}\text{C}$			mA
R _O	Open-loop output imp	pedance	V _S = 5.5 V, f = 100 Hz, T _A = 25°C	570		Ω
POWER				4.0		.,
Vs	Specified voltage range			1.8	5.5	V
IQ	Quiescent current pe temperature	r amplifier, over	$V_S = 5 \text{ V}, I_O = 0 \text{ mA}, T_A = -40^{\circ}\text{C to } +125^{\circ}\text{C}$	150	250	μΑ
TEMPER	ATURE					т
	Specified range			-40	125	°C
T _{stg}	Storage range			-65	150	°C

⁽¹⁾ Parameters with minimum or maximum specification limits are 100% production tested at 25°C, unless otherwise noted. Over-temperature limits are based on characterization and statistical analysis.

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⁽²⁾ Specified by design and characterization; not production tested.

³⁾ Signifies the slower value of the positive or negative slew rate.

⁽⁴⁾ Third-order filter; bandwidth = 80 kHz at −3 dB.

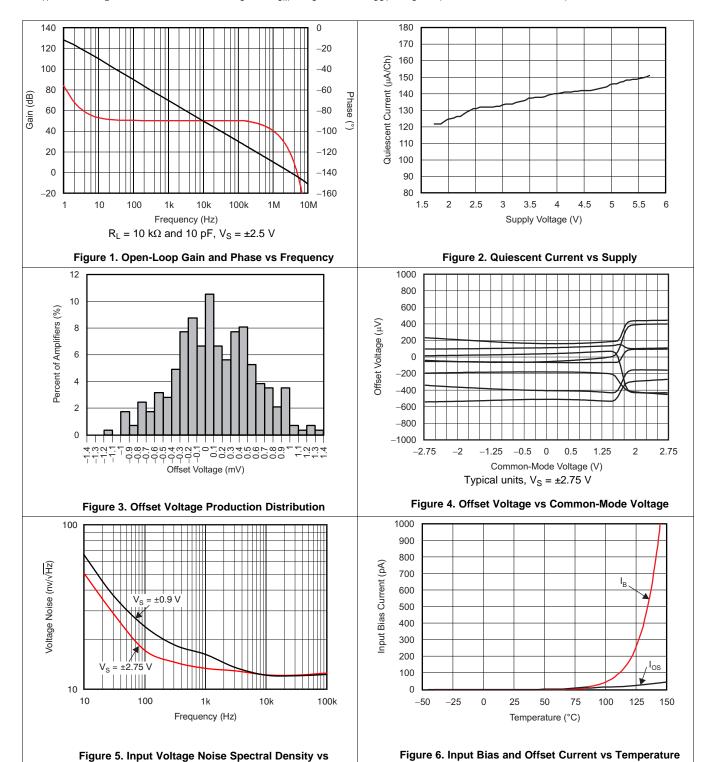
6.8 Typical Characteristics

Table 1. Table of Graphs

TITLE	FIGURE
Open-Loop Gain and Phase vs Frequency	Figure 1
Quiescent Current vs Supply Voltage	Figure 2
Offset Voltage Production Distribution	Figure 3
Offset Voltage vs Common-Mode Voltage (Maximum Supply)	Figure 4
Input Voltage Noise Spectral Density vs Frequency (1.8 V, 5.5 V)	Figure 5
Input Bias and Offset Current vs Temperature	Figure 6
Output Voltage Swing vs Output Current (Overtemperature)	Figure 7
Small-Signal Overshoot vs Load Capacitance	Figure 8
Small-Signal Step Response, Noninverting (1.8 V)	Figure 9
Large-Signal Step Response, Noninverting (1.8 V)	Figure 10
No Phase Reversal	Figure 11
Channel Separation vs Frequency (Dual)	Figure 12
EMIRR	Figure 13

6.9 Typical Characteristics

at T_A = 25°C, R_L = 10 k Ω connected to V_S / 2, V_{CM} = V_S / 2, and V_{OUT} = V_S / 2 (unless otherwise noted)



Frequency

TEXAS INSTRUMENTS

Typical Characteristics (continued)

at $T_A = 25$ °C, $R_L = 10$ k Ω connected to V_S / 2, $V_{CM} = V_S$ / 2, and $V_{OUT} = V_S$ / 2 (unless otherwise noted)

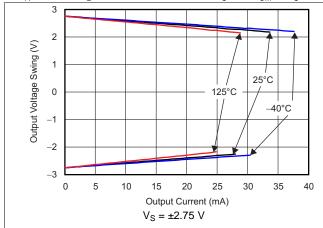


Figure 7. Output Voltage Swing vs Output Current (Overtemperature)

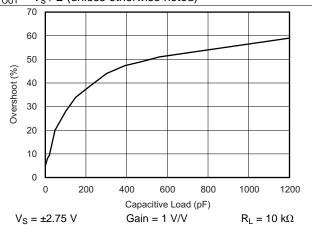


Figure 8. Small-Signal Overshoot vs Load Capacitance

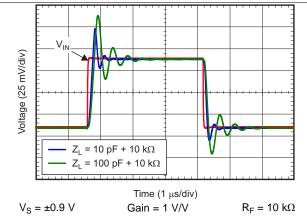


Figure 9. Small-Signal Pulse Response (Noninverting)

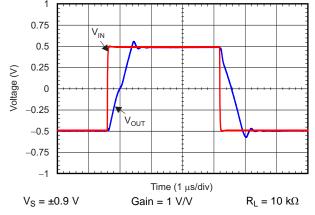
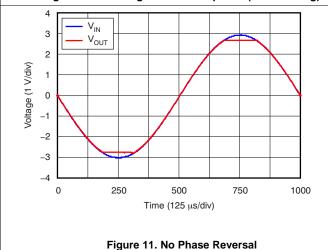


Figure 10. Large-Signal Pulse Response (Noninverting)



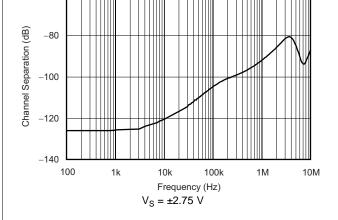


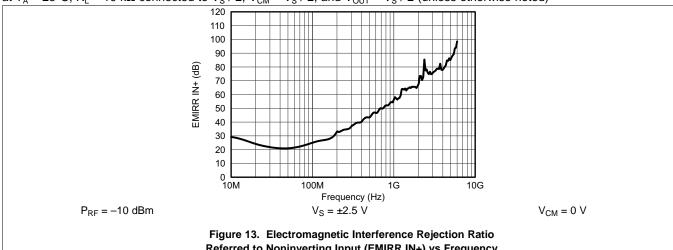
Figure 12. Channel Separation vs Frequency (TLV2314)





Typical Characteristics (continued)

at $T_A = 25$ °C, $R_L = 10$ k Ω connected to V_S / 2, $V_{CM} = V_S$ / 2, and $V_{OUT} = V_S$ / 2 (unless otherwise noted)



Referred to Noninverting Input (EMIRR IN+) vs Frequency



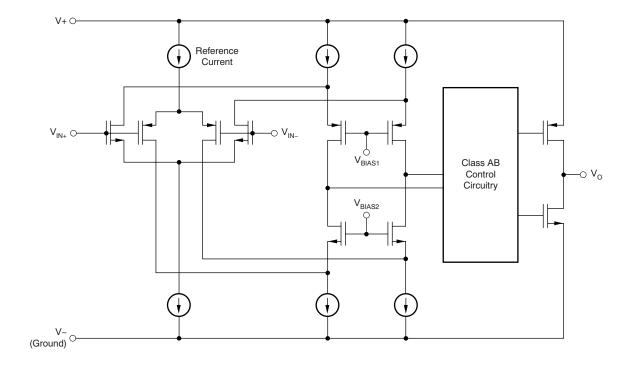
7 Detailed Description

7.1 Overview

The TLVx314-Q1 is a family of low-power, rail-to-rail input and output operational amplifiers specifically designed for portable applications. These devices operate from 1.8 V to 5.5 V, are unity-gain stable, and suitable for a wide range of general-purpose applications. The class AB output stage is capable of driving \leq 10-k Ω loads connected to any point between V+ and ground. The input common-mode voltage range includes both rails, and allows the TLVx314-Q1 to be used in virtually any single-supply application. Rail-to-rail input and output swing significantly increases dynamic range, especially in low-supply applications, and makes these devices suitable for driving sampling analog-to-digital converters (ADCs).

The TLVx314-Q1 family features 3-MHz bandwidth and $1.5\text{-V}/\mu\text{s}$ slew rate with only $150\text{-}\mu\text{A}$ supply current per channel, providing good ac performance at very-low-power consumption. DC applications are also well served with a very low input noise voltage of 14 nV / $\sqrt{\text{Hz}}$ at 1 kHz, low input bias current (0.2-pA), and a typical input offset voltage of 0.5 mV.

7.2 Functional Block Diagram



7.3 Feature Description

7.3.1 Operating Voltage

The TLVx314-Q1 series of operational amplifiers is fully specified and ensured for operation from 1.8 V to 5.5 V. In addition, many specifications apply from –40°C to +125°C. Parameters that vary significantly with operating voltages or temperature are provided in the *Typical Characteristics* section. Bypass power-supply pins with 0.01-μF ceramic capacitors.

7.3.2 Rail-to-Rail Input

The input common-mode voltage range of the TLVx314-Q1 extends 200 mV beyond the supply rails. This performance is achieved with a complementary input stage: an N-channel input differential pair in parallel with a P-channel differential pair, as shown in the *Functional Block Diagram*. The N-channel pair is active for input voltages close to the positive rail, typically (V+) - 1.3 V to 200 mV above the positive supply, and the P-channel pair is on for inputs from 200 mV below the negative supply to approximately (V+) - 1.3 V. There is a small transition region, typically (V+) - 1.4 V to (V+) - 1.2 V, in which both pairs are on. This 200-mV transition region may vary up to 300 mV with process variation. Thus, the transition region (with both stages on) ranges from (V+) - 1.7 V to (V+) - 1.5 V on the low end, up to (V+) - 1.1 V to (V+) - 0.9 V on the high end. Within this transition region, PSRR, CMRR, offset voltage, offset drift, and THD can degrade compared to device operation outside this region.

7.3.3 Rail-to-Rail Output

Designed as a micro-power, low-noise operational amplifier, the TLVx314-Q1 delivers a robust output drive capability. A class AB output stage with common-source transistors achieves full rail-to-rail output swing capability. For resistive loads up to 10-k Ω , the output typically swings to within 5 mV of either supply rail regardless of the applied power-supply voltage . Different load conditions change the ability of the amplifier to swing close to the rails, as shown in Figure 7.

7.3.4 Common-Mode Rejection Ratio (CMRR)

The CMRR for the TLVx314-Q1 is specified in several ways so the best match for a given application can be used; see the *Electrical Characteristics* table. First, the CMRR of the device in the common-mode range below the transition region $[V_{CM} < (V+) - 1.3 \text{ V}]$ is given. This specification is the best indicator of the capability of the device when the application requires using one of the differential input pairs. Second, the CMRR over the entire common-mode range is specified at $(V_{CM} = -0.2 \text{ V} \text{ to 5.7 V})$. This last value includes the variations measured through the transition region, as shown in Figure 4.

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Feature Description (continued)

7.3.5 Capacitive Load and Stability

The TLVx314-Q1 is designed for applications where driving a capacitive load is required. As with all operational amplifiers, there may be specific instances where the TLVx314-Q1 can become unstable. The particular operational amplifier circuit configuration, layout, gain, and output loading are some of the factors to consider when establishing whether or not an amplifier is stable in operation. An operational amplifier in the unity-gain (1 V/V) buffer configuration that drives a capacitive load exhibits a greater tendency to be unstable than an amplifier operated at a higher noise gain. The capacitive load, in conjunction with the operational amplifier output resistance, creates a pole within the feedback loop that degrades the phase margin. The degradation of the phase margin increases when capacitive loading increases. When operating in the unity-gain configuration, the TLVx314-Q1 remains stable with a pure capacitive load up to approximately 1 nF. The equivalent series resistance (ESR) of some very large capacitors (C_L capacitors with a value greater than 1 μ F) is sufficient to alter the phase characteristics in the feedback loop so the amplifier remains stable. Increasing the amplifier closed-loop gain allows the amplifier to drive increasingly larger capacitance. This increased capability is evident when measuring the overshoot response of the amplifier at higher voltage gains, as shown in Figure 8.

Inserting a small resistor (typically $10-\Omega$ to $20-\Omega$) can increase the capacitive load drive of the amplifier in a unity-gain configuration, as shown in Figure 14. This resistor significantly reduces the overshoot and ringing associated with large capacitive loads. One possible problem with this technique, however, is that a voltage divider is created with the added series resistor and any resistor connected in parallel with the capacitive load. The voltage divider introduces a gain error at the output that reduces the output swing.

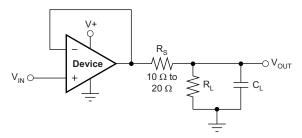


Figure 14. Improving Capacitive Load Drive

7.3.6 EMI Susceptibility and Input Filtering

Operational amplifiers vary with regard to the susceptibility of the device to electromagnetic interference (EMI). If conducted EMI enters the operational amplifier, the dc offset at the amplifier output can shift from the nominal value when EMI is present. This shift is a result of signal rectification associated with the internal semiconductor junctions. Although EMI can affect all operational amplifier pin functions, the signal input pins are likely to be the most susceptible. The TLVx314-Q1 operational amplifier family incorporates an internal input low-pass filter that reduces the amplifiers response to EMI. The filter provides common-mode and differential mode filtering. The filter is designed for a cutoff frequency of approximately 80 MHz (–3 dB), with a roll-off of 20 dB per decade.

Texas Instruments has developed the ability to accurately measure and quantify the immunity of an operational amplifier over a broad frequency spectrum extending from 10 MHz to 6 GHz. The EMI rejection ratio (EMIRR) metric allows operational amplifiers to be directly compared to the EMI immunity. Figure 13 illustrates the testing results on the TLVx314-Q1. For more detailed information, see *EMI Rejection Ratio of Operational Amplifiers* (SBOA128), available for download from www.ti.com.

7.4 Device Functional Modes

The TLVx314-Q1 family has a single functional mode. These devices are powered on as long as the power-supply voltage is between 1.8 V (±0.9 V) and 5.5 V (±2.75 V).

6 Submit Documentation Feedback



8 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

The TLVx314-Q1 device is a low-power, rail-to-rail input and output operational amplifier specifically designed for portable applications. These devices operate from 1.8 V to 5.5 V, are unity-gain stable, and suitable for a wide range of general-purpose applications. The class AB output stage is capable of driving \leq 10-k Ω loads connected to any point between V+ and ground. The input common-mode voltage range includes both rails, and allows the TLVx314-Q1 family to be used in virtually any single-supply application. Rail-to-rail input and output swing significantly increases dynamic range, especially in low-supply applications, and makes the device suitable for driving sampling analog-to-digital converters (ADCs).

The TLVx314-Q1 features a 3-MHz bandwidth and 1.5-V/ μ s slew rate with only 150- μ A supply current per channel, providing good ac performance at very-low-power consumption. DC applications are also well served with a very-low input noise voltage of 14 nV/ $\sqrt{\text{Hz}}$ at 1 kHz, low-input bias current (0.2 pA), and a typical input offset voltage of 0.5 mV.

8.2 Typical Application

A typical application for an operational amplifier is an inverting amplifier, as shown in Figure 15. An inverting amplifier takes a positive voltage on the input and outputs a signal inverted to the input, making a negative voltage of the same magnitude. In the same manner, the amplifier also makes negative input voltages positive on the output. In addition, amplification can be added by selecting the input resistor (R_I) and the feedback resistor (R_F) .

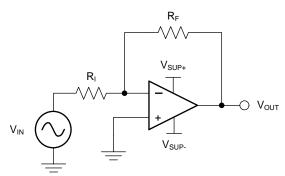


Figure 15. Application Schematic

8.2.1 Design Requirements

The supply voltage must be chosen to be larger than the input voltage range and the desired output range. The limits of the input common-mode range (V_{CM}) and the output voltage swing to the rails (V_{O}) must also be considered. For instance, this application scales a signal of ± 0.5 V (1 V) to ± 1.8 V (3.6 V). Setting the supply at ± 2.5 V is sufficient to accommodate this application.

8.2.2 Detailed Design Procedure

Calculate the gain required by the inverting amplifier using Equation 1 and Equation 2:

$$A_{V} = \frac{V_{OUT}}{V_{IN}} \tag{1}$$

$$A_{V} = \frac{1.8}{-0.5} = -3.6 \tag{2}$$

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TEXAS INSTRUMENTS

Typical Application (continued)

When the desired gain is determined, select a value for R_I or R_F . Selecting a value in the kilohm range is desirable for general-purpose applications because the amplifier circuit uses currents in the milliamp range. This milliamp current range ensures the device does not draw too much current. The trade-off is that very large resistors (hundreds of kilohms) draw the smallest current, but generate the highest noise. Very small resistors (hundreds of ohms) generate low noise but draw high current. This example uses 10 k Ω for R_I , and R_F uses 36 k Ω . These values are calculated using Equation 3:

$$A_{V} = -\frac{R_{F}}{R_{I}} \tag{3}$$

8.2.3 Application Curve

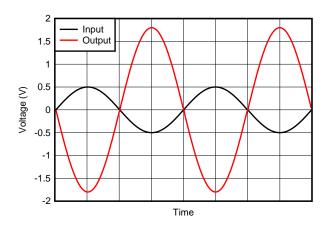
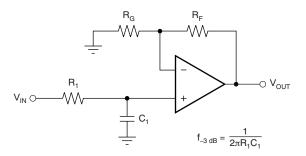


Figure 16. Inverting Amplifier Input and Output

8.3 System Examples

When receiving low-level signals, limiting the bandwidth of the incoming signals into the system is often required. The simplest way to establish this limited bandwidth is to place an RC filter at the noninverting terminal of the amplifier, as Figure 17 shows.



$$\frac{V_{OUT}}{V_{IN}} = \left(1 + \frac{R_F}{R_G}\right) \left(\frac{1}{1 + sR_1C_1}\right)$$

Figure 17. Single-Pole, Low-Pass Filter

If even more attenuation is needed, a multiple pole filter is required. The Sallen-Key filter can be used for this task, as Figure 18 shows. For best results, the amplifier must have a bandwidth that is eight to ten times the filter frequency bandwidth. Failure to follow this guideline can result in phase shift of the amplifier.

8 Submit Documentation Feedback



System Examples (continued)

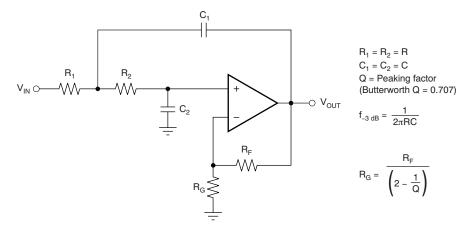


Figure 18. Two-Pole, Low-Pass, Sallen-Key Filter

9 Power Supply Recommendations

The TLVx314-Q1 family is specified for operation from 1.8 V to 5.5 V (±0.9 V to ±2.75 V); many specifications apply from -40°C to +125°C. *Typical Characteristics* presents parameters that can exhibit significant variance with regard to operating voltage or temperature.

CAUTION

Supply voltages larger than 7 V can permanently damage the device (see the *Absolute Maximum Ratings* table).

Place $0.1-\mu F$ bypass capacitors close to the power-supply pins to reduce errors coupling in from noisy or high-impedance power supplies. For more detailed information on bypass capacitor placement; see *Layout Guidelines*.

9.1 Input and ESD Protection

The TLVx314-Q1 family incorporates internal electrostatic discharge (ESD) protection circuits on all pins. In the case of input and output pins, this protection primarily consists of current-steering diodes connected between the input and power-supply pins. These ESD protection diodes provide in-circuit, input overdrive protection, as long as the current is limited to 10 mA, as stated in the *Absolute Maximum Ratings* table. Figure 19 shows how a series input resistor can be added to the driven input to limit the input current. The added resistor contributes thermal noise at the amplifier input, which must be kept to a minimum in noise-sensitive applications.

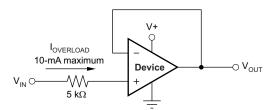


Figure 19. Input Current Protection

20



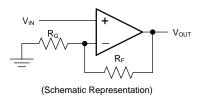
10 Layout

10.1 Layout Guidelines

For best operational performance of the device, use good printed circuit board (PCB) layout practices, including:

- Noise can propagate into analog circuitry through the power pins of the circuit as a whole and the
 operational amplifier. Use bypass capacitors to reduce the coupled noise by providing low-impedance
 power sources local to the analog circuitry.
 - Connect low-ESR, 0.1-µF ceramic bypass capacitors between each supply pin and ground, placed as close to the device as possible. A single bypass capacitor from V+ to ground is applicable for singlesupply applications.
- Separate grounding for analog and digital portions of the circuitry is one of the simplest and most
 effective methods of noise suppression. One or more layers on multilayer PCBs are typically devoted to
 ground planes. A ground plane helps distribute heat and reduces EMI noise pickup. Take care to
 physically separate digital and analog grounds, paying attention to the flow of the ground current. For
 more detailed information, see Circuit Board Layout Techniques (SLOA089).
- To reduce parasitic coupling, run the input traces as far away from the supply or output traces as possible. If these traces cannot be kept separate, crossing the sensitive trace perpendicularly is much better than crossing in parallel with the noisy trace.
- Place the external components as close to the device as possible. Keep R_F and R_G close to the inverting input in order to minimize parasitic capacitance, as shown in Figure 20.
- Keep the length of input traces as short as possible. Always remember that the input traces are the most sensitive part of the circuit.
- Consider a driven, low-impedance guard ring around the critical traces. A guard ring can significantly reduce leakage currents from nearby traces that are at different potentials.

10.2 Layout Example



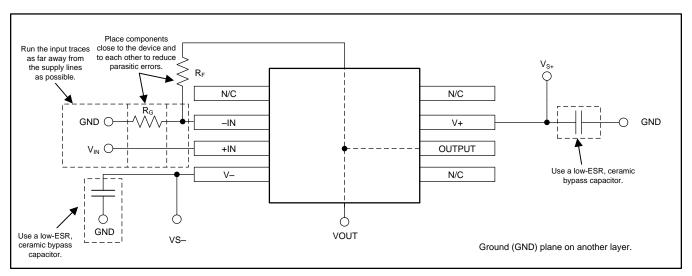


Figure 20. Operational Amplifier Board Layout for Noninverting Configuration

11 Device and Documentation Support

11.1 Device Support

11.1.1 Development Support

11.2 Documentation Support

11.2.1 Related Documentation

For related documentation, see the following:

- EMI Rejection Ratio of Operational Amplifiers (SBOA128).
- Circuit Board Layout Techniques (SLOA089).
- QFN/SON PCB Attachment (SLUA271).
- Quad Flatpack No-Lead Logic Packages (SCBA017).

11.3 Related Links

Table 2 lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 2. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY	
TLV314-Q1	Click here	Click here	Click here	Click here	Click here	
TLV2314-Q1	Click here	Click here	Click here	Click here	Click here	
TLV4314-Q1	Click here	Click here	Click here	Click here	Click here	

11.4 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

11.5 Trademarks

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

11.6 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

11.7 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.





12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGE OPTION ADDENDUM



1-Jan-2017

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing		Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TLV2314QDGKRQ1	PREVIEW	VSSOP	DGK	8	2500	TBD	Call TI	Call TI	-40 to 125		
TLV2314QDRQ1	PREVIEW	SOIC	D	8	2500	TBD	Call TI	Call TI	-40 to 125		
TLV314QDBVRQ1	ACTIVE	SOT-23	DBV	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	16SD	Samples
TLV314QDBVTQ1	ACTIVE	SOT-23	DBV	5	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	16SD	Samples
TLV4314QPWRQ1	PREVIEW	TSSOP	PW	14	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	V4314Q1	

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.



PACKAGE OPTION ADDENDUM

1-Jan-2017

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OTHER QUALIFIED VERSIONS OF TLV2314-Q1, TLV314-Q1, TLV4314-Q1:

• Catalog: TLV2314, TLV314, TLV4314

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

PW (R-PDSO-G14)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
 - Sody length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



PW (R-PDSO-G14)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AA.



DBV (R-PDSO-G5)

PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
- D. Falls within JEDEC MO-178 Variation AA.



DBV (R-PDSO-G5)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.



DGK (S-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- E. Falls within JEDEC MO-187 variation AA, except interlead flash.



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